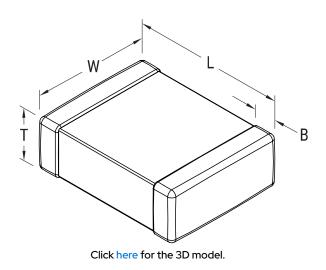




CBR-SMD RF COG, Ceramic, 7.6 pF, +/-0.5 pF, 25 VDC, COG, SMD, Fixed, RF, Ultra High Q, Low ESR, Class I, 0201



| General Information | | |
|--------------------------|---|--|
| Series | CBR-SMD RF COG | |
| Style | SMD Chip | |
| Description | SMD, Fixed, RF, Ultra High Q, Low ESR, Class I | |
| Features | Ultra High Q, Low ESR, Class I | |
| RoHS | Yes | |
| Termination | Tin | |
| Marking | No | |
| AEC-Q200 | No | |
| Typical Component Weight | 0.3 mg | |
| Notes | Solder Reflow Only. | |
| Shelf Life | 78 Weeks | |
| MSL | 1 | |

| Dimensions | |
|------------|------------------|
| Chip Size | 0201 |
| L | 0.6mm +/-0.03mm |
| W | 0.3mm +/-0.03mm |
| Т | 0.3mm +/-0.03mm |
| В | 0.15mm +/-0.05mm |

| Chip Size | 0201 | Capacitance | 7.6 pF |
|--------------------------|--------------------------|---------------------------------|---------------------|
| L | 0.6mm +/-0.03mm | Tolerance | +/-0.5 pF |
| W | 0.3mm +/-0.03mm | Voltage DC | 25 VDC |
| Т | 0.3mm +/-0.03mm | Dielectric Withstanding Voltage | 62.5 VDC |
| В | 0.15mm +/-0.05mm | Temperature Range | -55/+125°C |
| | | Temp. Coefficient | COG |
| Packaging Specifications | | Dissipation Factor | O.181% |
| Packaging | T&R, 180mm, Plastic Tape | Aging Rate | 0% Loss/Decade Hour |
| Packaging Quantity | 15000 | Insulation Resistance | 10 GOhms |
| | | Quality Factor | 552 |

Specifications

| Statements of suitability for certain applications are based on our knowledge of typical operating conditions for such applications, but are not intended to constitute - and |
|--|
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